

Search Notes



Application No.

10/665,262

Examiner

Ernest F. Karlsen

Applicant(s)

MAENO, SHUICHI

Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner
324	500 501 686 713 750 751 765	1/21/2005	E.F.K.
156	345.24	1/21/2005	E.F.K.
156	345.28	1/21/2005	E.F.K.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
substrate same charging adj voltage measuring adj electrode same measuring adj capacitor	1/21/2005	E.F.K.
ion adj beam same plasma asame charging adj voltage	1/21/2005	E.F.K.